


<b>Search Notes</b>  	<b>Application/Control No.</b>  10582594	<b>Applicant(s)/Patent Under Reexamination</b>  BEIER ET AL.
	<b>Examiner</b>  Patrick F O'Reilly III	<b>Art Unit</b>  3749

SEARCHED			
Class	Subclass	Date	Examiner
454	71, 72, 76	7/28/2008	PFO3
62	172	7/28/2008	PFO3

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (USPAT, US-PGPUB, USOCR, EPO, JPO DERWENT, IBM_TDB) searched - printout attached.	7/27/2008; 7/28/2008	PFO3
PLUS search performed - refer to search results in eDAN.	7/25/2008	STIC
Inventor name search performed in PALM and EAST.	7/28/2008	PFO3

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner